



Press Release

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Industry Leaders Seeking Adaptive Test Solutions Chip Manufacturers and Test Software Vendors Share Roadmaps

A subgroup of members of the [Die Products Consortium](#), the AC Defects test team, is focused on a new generation of test and reliability methods for leading edge semiconductor devices known as Adaptive Test. The group sponsored a unique meeting with third party vendors of Adaptive Test solutions in Santa Clara, CA during the 2007 International Test Conference held in October.

Adaptive Test is a term used to describe a broad array of statistical methods for improving semiconductor test by adjusting the test plan based upon feedback from the test environment itself. This is a major departure from traditional test methods that follow a static plan and as has come to take on different meanings for different people. The AC Defects group surveyed the various ways in which adaptive test concepts have been proposed, implemented or anticipated by the member companies' IC testing strategies. The team agreed that, to facilitate an effective evolution of the algorithms, tools and infrastructure that will be required for tomorrow's test challenges the group should provide a summary of the findings to the commercial providers of adaptive test solutions.

Three vendors of adaptive test solutions were invited and attended the session: Pintail Technologies, Plano, Texas, OptimalTest, Nes-Ziona, Israel and Test Advantage Inc., Tempe, Arizona held in Santa Clara on October 22, 2007.

During the meeting, representatives of DPC member companies presented the "highest priority" applications of adaptive test from within the DPC subgroup and the corresponding support that is needed from the vendors. The group acknowledged the breath of methodologies that are currently in use and/or being planned for use.

The meeting was considered an important first step in moving the adaptive test solutions into a plug and play mode for IC manufacturers and third party test houses. Discussions

are underway regarding potential follow-up meetings and/or activities. For more information, please contact Larry Gilg, Managing Director, DPC.

The Die Products Consortium (DPC) is a program of [Dynalog Systems, Inc.](#) Under the DPC program, Dynalog Systems, Inc. has invited a group of leading microelectronics companies to collaborate in enlarging the markets for die products worldwide. The DPC is headquartered in Austin, Texas.

About Pintail Technologies

Pintail Technologies is a semiconductor test improvement and yield learning company that provides adaptive test software to reduce the cost of test and increase production output and quality through existing test equipment and programs. Pintail has created the first test improvement solutions to combine real-time, on-line, adaptive test with powerful web-based database applications. Fabless and integrated device manufacturers (IDM) worldwide, in collaboration with leading assembly and test suppliers use Pintail tools to increase competitive advantage and improve responsiveness to test issues. Pintail has sales offices in Dallas, Austin, San Jose, Seoul, Singapore, and Taiwan. See www.pintail.com.